

40V N-Ch Power MOSFET

Feature

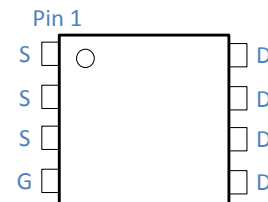
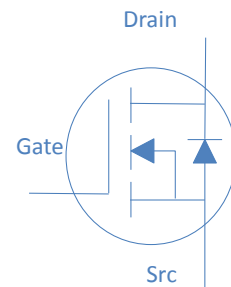
- Optimized for high speed switching, Logic Level
- Enhanced Body diode dv/dt capability
- Enhanced Avalanche Ruggedness
- 100% UIS Tested, 100% Rg Tested
- Lead Free, Halogen Free

Application

- Synchronous Rectification in SMPS
- Hard Switching and High Speed Circuit
- Power Tools
- UPS
- Motor Control

V_{DS}		40	V
$R_{DS(on),typ}$	$V_{GS}=10V$	1.4	$m\Omega$
$R_{DS(on),typ}$	$V_{GS}=4.5V$	1.8	$m\Omega$
I_D (Silicon Limited)		181	A
I_D (Package Limited)		60	A

DFN5x6



Part Number	Package	Marking
HTN020N04P	DFN5x6	TN020N04P

Absolute Maximum Ratings at $T_j=25$ (unless otherwise specified)

Parameter	Symbol	Conditions	Value	Unit
Continuous Drain Current (Silicon Limited)	I_D	$T_C=25$	181	A
		$T_C=100$	115	
		$T_C=25$	60	
Continuous Drain Current (Package Limited)		$T_C=25$	60	
Drain to Source Voltage	V_{DS}	-	40	V
Gate to Source Voltage	V_{GS}	-	± 20	V
Pulsed Drain Current	I_{DM}	-	460	A
Avalanche Energy, Single Pulse	E_{AS}	$L=0.4mH, T_C=25$	320	mJ
Power Dissipation	P_D	$T_C=25$	119	W
Operating and Storage Temperature	T_J, T_{stg}	-	-55 to 150	

Absolute Maximum Ratings

Parameter	Symbol	Max	Unit
Thermal Resistance Junction-Case	$R_{\theta JC}$	1.05	W^{-1}
Thermal Resistance Junction-Ambient	$R_{\theta JA}$	55	W^{-1}

Electrical Characteristics at $T_j=25$ (unless otherwise specified)
Static Characteristics

Parameter	Symbol	Conditions	Value			Unit
			min	typ	max	
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=250\mu A$	40	-	-	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS}=V_{DS}, I_D=250\mu A$	1	1.8	2.2	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{GS}=0V, V_{DS}=40V, T_j=25$	-	-	1	μA
		$V_{GS}=0V, V_{DS}=40V, T_j=100$	-	-	100	
Gate to Source Leakage Current	I_{GSS}	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 100	nA
Drain to Source on Resistance	$R_{DS(on)}$	$V_{GS}=10V, I_D=20A$	-	1.4	2	$m\Omega$
		$V_{GS}=4.5V, I_D=20A$	-	1.8	3	$m\Omega$
Transconductance	g_{fs}	$V_{DS}=5V, I_D=20A$	-	120	-	S
Gate Resistance	R_G	$V_{GS}=0V, V_{DS}$ Open, $f=1MHz$	-	0.85	-	Ω

Dynamic Characteristics

Input Capacitance	C_{iss}	$V_{GS}=0V, V_{DS}=20V, f=1MHz$	-	7356	-	pF
Output Capacitance	C_{oss}		-	814	-	
Reverse Transfer Capacitance	C_{rss}		-	547	-	
Total Gate Charge (10V)	$Q_g(10V)$	$V_{DD}=20V, I_D=20A, V_{GS}=10V$	-	135	-	nC
Total Gate Charge (4.5V)	$Q_g(4.5V)$		-	70	-	
Gate to Source Charge	Q_{gs}		-	20	-	
Gate to Drain (Miller) Charge	Q_{gd}		-	35	-	
Turn on Delay Time	$t_{d(on)}$	$V_{DD}=20V, I_D=20A, V_{GS}=10V, R_G=10\Omega,$	-	26	-	ns
Rise time	t_r		-	21	-	
Turn off Delay Time	$t_{d(off)}$		-	75	-	
Fall Time	t_f		-	25	-	

Reverse Diode Characteristics

Diode Forward Voltage	V_{SD}	$V_{GS}=0V, I_F=20A$	-	0.9	1.2	V
Reverse Recovery Time	t_{rr}	$V_R=20V, I_F=20A, di_F/dt=200A/\mu s$	-	40	-	ns
Reverse Recovery Charge	Q_{rr}		-	50	-	nC



Figure 3. On-Resistance vs. Drain Current and Gate Voltage

Figure 7. Typical Gate-Charge vs. Gate-to-Source Voltage

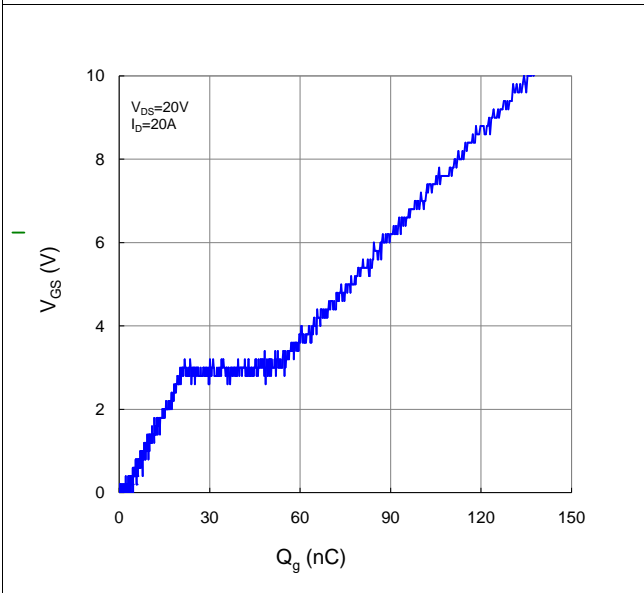


Figure 8. Typical Capacitance vs. Drain-to-Source Voltage

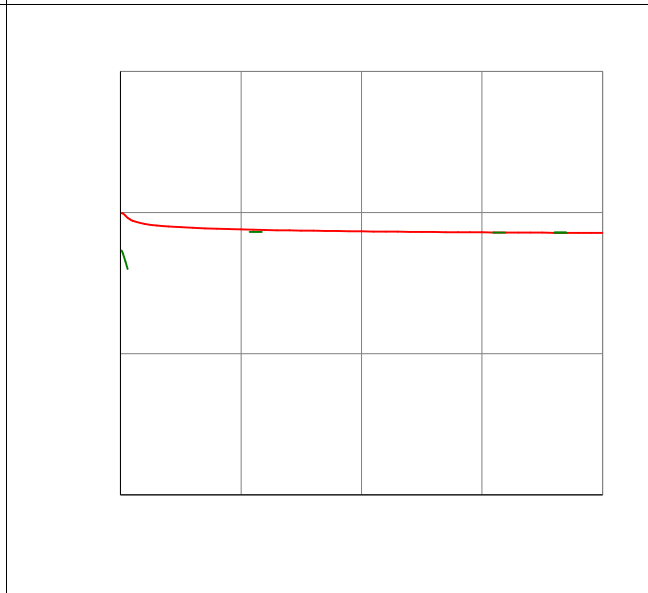


Figure 9. Maximum Safe Operating Area

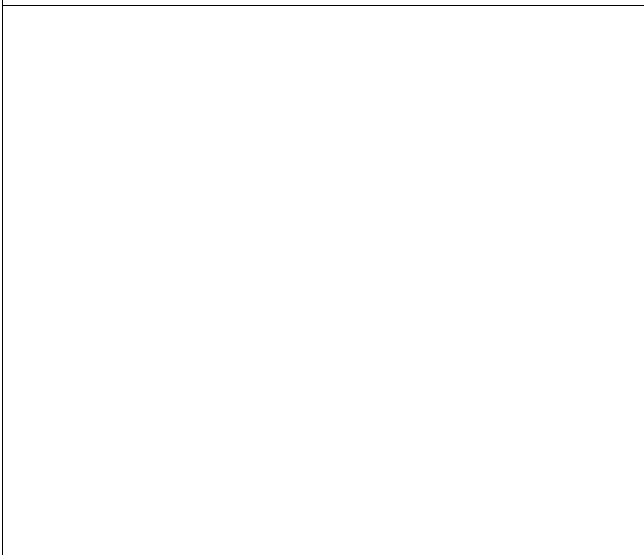


Figure 10. Maximum Drain Current vs. Case Temperature

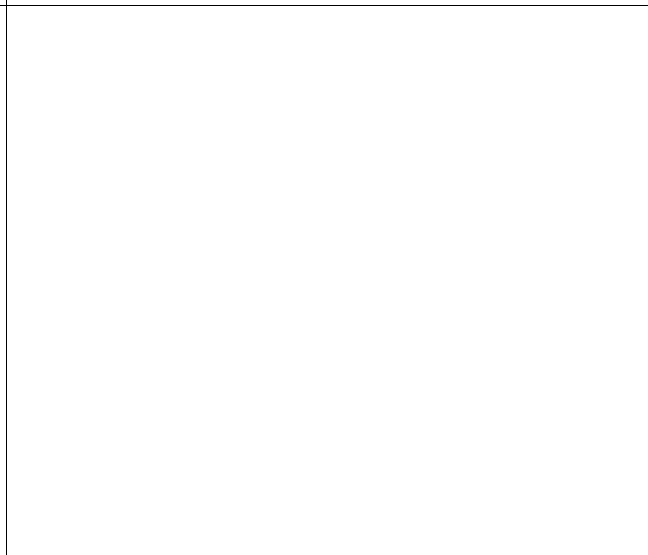
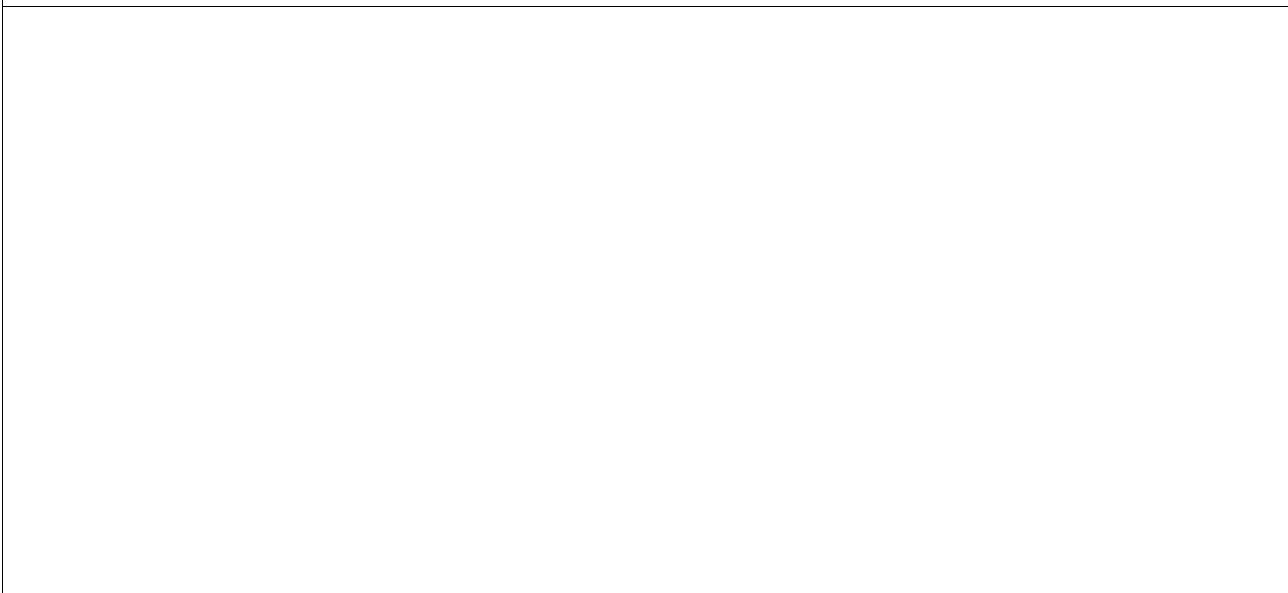
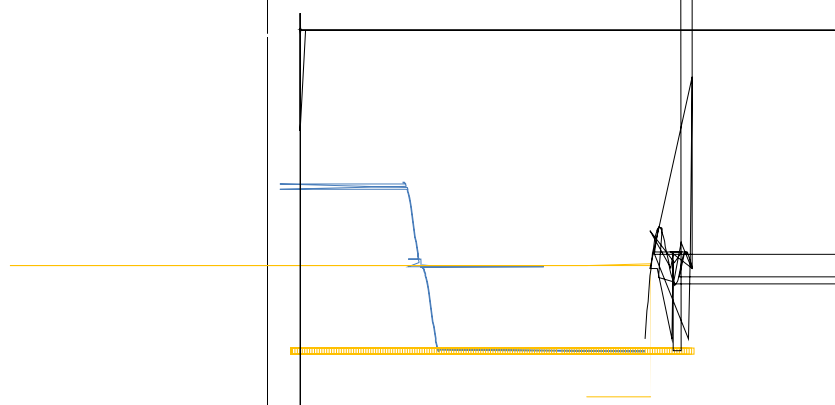


Figure 11. Normalized Maximum Transient Thermal Impedance, Junction-to-Case





Inductive switching Test



Gate Charge Test

Uclamped Inductive Switching (UIS) Test

Diode Recovery Test

